



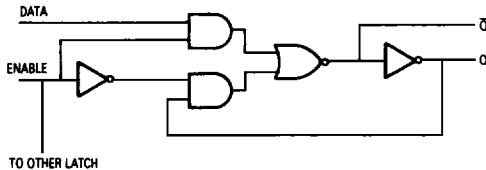
# Military 54LS375

## 4-Bit Bistable Latch

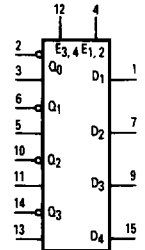
ELECTRICALLY TESTED PER:  
MIL-M-38510/31604

The 54LS375 is a 4-Bit D-Type Latch for use as temporary storage for binary information between processing limits and input/output or indicator units. When the Enable (E) is HIGH, information present at the D input will be transferred to the Q output and, if E is HIGH, the Q output will follow the input. When E goes LOW, the information present at the D input prior to its setup time will be retained at the Q outputs.

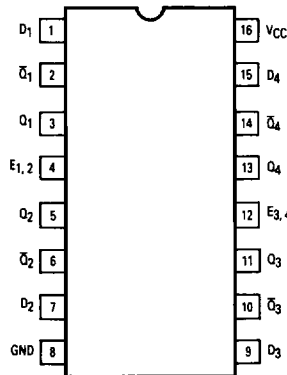
### LOGIC DIAGRAM



### LOGIC SYMBOL



### CONNECTION DIAGRAM



### PIN ASSIGNMENTS

FUNCTION	DIL	FLATS	LCC	BURN-IN (CONDITION A)
D <sub>1</sub>	1	1	2	V <sub>CC</sub>
Q <sub>1</sub>	2	2	3	OPEN
Q <sub>1</sub>	3	3	4	V <sub>CC</sub>
E <sub>n1-2</sub>	4	4	5	V <sub>CC</sub>
Q <sub>2</sub>	5	5	7	V <sub>CC</sub>
Q <sub>2</sub>	6	6	8	OPEN
D <sub>2</sub>	7	7	9	V <sub>CC</sub>
GND	8	8	10	GND
D <sub>3</sub>	9	9	12	V <sub>CC</sub>
Q <sub>3</sub>	10	10	13	OPEN
Q <sub>3</sub>	11	11	14	V <sub>CC</sub>
E <sub>n3-4</sub>	12	12	15	V <sub>CC</sub>
Q <sub>4</sub>	13	13	17	V <sub>CC</sub>
Q <sub>4</sub>	14	14	18	OPEN
D <sub>4</sub>	15	15	19	V <sub>CC</sub>
V <sub>CC</sub>	16	16	20	V <sub>CC</sub>

BURN-IN CONDITIONS:  
V<sub>CC</sub> = 5.0 V MIN/6.0 V MAX

### TRUTH TABLE (Each Latch)

t <sub>n</sub>	t <sub>n+1</sub>
D	Q
H	H
L	L

t<sub>n</sub> = Bit time before enable negative-going transition  
t<sub>n+1</sub> = Bit time after enable negative-going transition.

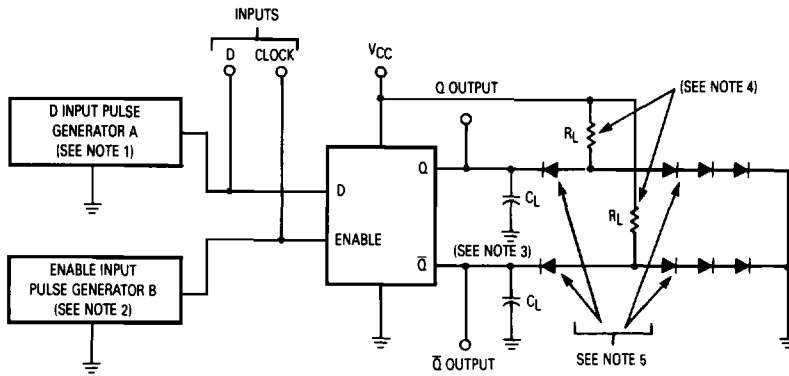
Pin Names	Loading (Note a)	
	HIGH	LOW
D <sub>1</sub> -D <sub>4</sub> Data Inputs	0.5 U.L.	0.25 U.L.
E <sub>0</sub> -E <sub>1</sub> Enable Input Latches 0, 1	2.0 U.L.	1.0 U.L.
E <sub>2</sub> -E <sub>3</sub> Enable Input Latches 2, 3	2.0 U.L.	1.0 U.L.
Q <sub>1</sub> -Q <sub>4</sub> Latch Outputs (Note b)	10 U.L.	5(2.5) U.L.
$\bar{Q}$ <sub>1</sub> - $\bar{Q}$ <sub>4</sub> Complimentary Latch Outputs (Note b)	10 U.L.	5(2.5) U.L.

#### NOTES:

- One TTL Unit Load (U.L.) = 40  $\mu$ A HIGH/1.6 mA LOW.
- The Output LOW drive factor is 2.5 U.L. for Military (54) and 5 U.L. for commercial (74) Temperature Ranges.

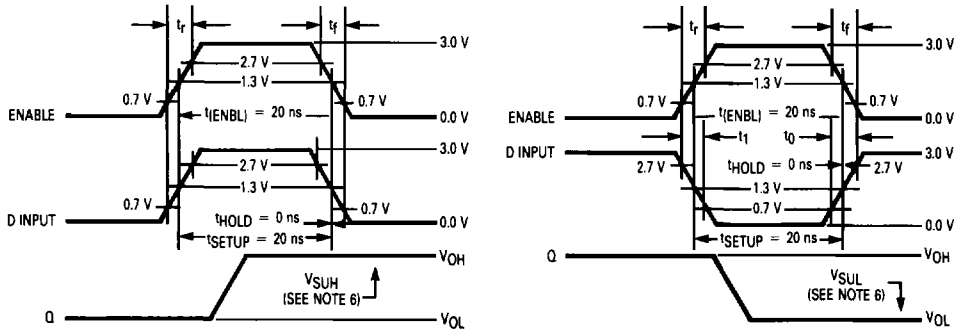
# 54LS375

## AC TEST CIRCUIT

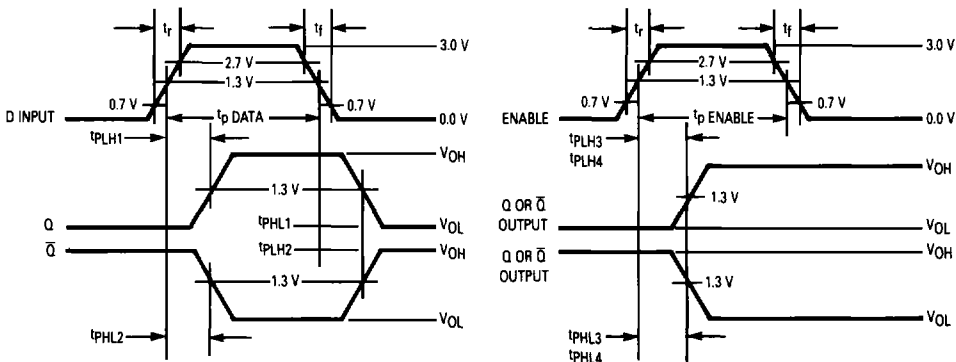


## WAVEFORMS

### Switching Test Circuit and Waveforms



### Setup and Hold Waveforms



54LS375

Symbol	Parameter	Limits						Units	Test Condition (Unless Otherwise Specified)
		+25°C		+125°C		-55°C			
		Subgroup 1		Subgroup 2		Subgroup 3			
		Min	Max	Min	Max	Min	Max		
V <sub>OH</sub>	Logical "1" Output Voltage	2.5		2.5		2.5		V	V <sub>CC</sub> = 4.5 V, I <sub>OH</sub> = -0.4 mA, V <sub>IH</sub> = 2.0 V or 0.7 V per truth table, Enable = (See Note 7).
V <sub>OL</sub>	Logical "0" Output Voltage		0.4		0.4		0.4	V	V <sub>CC</sub> = 4.5 V, I <sub>OL</sub> = 4.0 mA, V <sub>IL</sub> = 0.7 V or 2.0 V per truth table, Enable = (See Note 7).
V <sub>IC</sub>	Input Clamping Voltage		-1.5					V	V <sub>CC</sub> = 4.5 V, I <sub>IN</sub> = -18 mA, other inputs are open.
I <sub>IH</sub>	Logical "1" Input Current (D inputs)		20		20		20	μA	V <sub>CC</sub> = 5.5 V, V <sub>IH</sub> = 2.7 V, other input is open.
I <sub>IHH</sub>	Logical "1" Input Current (E <sub>n</sub> inputs)		80		80		80	μA	V <sub>CC</sub> = 5.5 V, V <sub>IH</sub> = GND, V <sub>IN</sub> (E <sub>n</sub> ) = 2.7 V.
I <sub>IH</sub>	Logical "1" Input Current (D inputs)		100		100		100	μA	V <sub>CC</sub> = 5.5 V, V <sub>IH</sub> = 5.5 V, V <sub>IN</sub> (E <sub>n</sub> ) = GND.
I <sub>IHH</sub>	Logical "1" Input Current (E <sub>n</sub> inputs)		400		400		400	μA	V <sub>CC</sub> = 5.5 V, V <sub>IH</sub> = GND, V <sub>IN</sub> (E <sub>n</sub> ) = 5.5 V.
I <sub>IL</sub>	Logical "0" Input Current (D inputs)	-0.16	-0.4	-0.16	-0.4	-0.16	-0.4	mA	V <sub>CC</sub> = 5.5 V, V <sub>IL</sub> = 0.4 V, V <sub>IN</sub> (E <sub>n</sub> ) = 4.5 V.
I <sub>IL</sub>	Logical "0" Input Current (E <sub>n</sub> inputs)	-0.64	-1.6	-0.64	-1.6	-0.64	-1.6	mA	V <sub>CC</sub> = 5.5 V, V <sub>IN</sub> (E <sub>n</sub> ) = 0.4 V, other input = 4.5 V.
I <sub>OS</sub>	Output Short Circuit Current	-15	-100	-15	-100	-15	-100	mA	V <sub>CC</sub> = 5.5 V, V <sub>IN</sub> (E <sub>n</sub> ) = 4.5 V, other input = GND.
I <sub>CC</sub>	Power Supply Current		12		12		12	mA	V <sub>CC</sub> = 5.5 V, V <sub>IN</sub> = 0 V (all inputs).
V <sub>IH</sub>	Logical "1" Input Voltage	2.0		2.0		2.0		V	V <sub>CC</sub> = 4.5 V.
V <sub>IL</sub>	Logical "0" Input Voltage		0.7		0.7		0.7	V	V <sub>CC</sub> = 4.5 V.
	Functional Tests	Subgroup 7		Subgroup 8A		Subgroup 8B			per Truth Table with V <sub>CC</sub> = 5.0 V, V <sub>INL</sub> = 0.4 V, and V <sub>INH</sub> = 2.5 V.

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## 54LS375

Symbol	Parameter	Limits						Units	Test Condition (Unless Otherwise Specified)
		+25°C		+125°C		-55°C			
		Subgroup 9		Subgroup 10		Subgroup 11			
		Min	Max	Min	Max	Min	Max		
t <sub>PHL1</sub> t <sub>PHL1</sub>	Propagation Delay Data-Output Data to Q	3.0	22 17	3.0	29 24	3.0	29 24	ns ns	V <sub>CC</sub> = 5.0 V, C <sub>L</sub> = 50 pF, R <sub>L</sub> = 2.0 kΩ ± 5.0%. V <sub>CC</sub> = 5.0 V, C <sub>L</sub> = 15 pF, R <sub>L</sub> = 2.0 kΩ ± 5.0%.
t <sub>PLH1</sub> t <sub>PLH1</sub>	Propagation Delay Data-Output Data to Q	3.0	32 27	3.0	42 37	3.0	42 37	ns ns	V <sub>CC</sub> = 5.0 V, C <sub>L</sub> = 50 pF, R <sub>L</sub> = 2.0 kΩ ± 5.0%. V <sub>CC</sub> = 5.0 V, C <sub>L</sub> = 15 pF, R <sub>L</sub> = 2.0 kΩ ± 5.0%.
t <sub>PHL2</sub> t <sub>PHL2</sub>	Propagation Delay Data-Output Data to Q̄	3.0	20 15	3.0	26 21	3.0	26 21	ns ns	V <sub>CC</sub> = 5.0 V, C <sub>L</sub> = 50 pF, R <sub>L</sub> = 2.0 kΩ ± 5.0%. V <sub>CC</sub> = 5.0 V, C <sub>L</sub> = 15 pF, R <sub>L</sub> = 2.0 kΩ ± 5.0%.
t <sub>PLH2</sub> t <sub>PLH2</sub>	Propagation Delay Data-Output Data to Q̄	3.0	25 20	3.0	32 27	3.0	32 27	ns ns	V <sub>CC</sub> = 5.0 V, C <sub>L</sub> = 50 pF, R <sub>L</sub> = 2.0 kΩ ± 5.0%. V <sub>CC</sub> = 5.0 V, C <sub>L</sub> = 15 pF, R <sub>L</sub> = 2.0 kΩ ± 5.0%.
t <sub>PHL3</sub> t <sub>PHL3</sub>	Propagation Delay Data-Output Enable to Q	3.0	30 25	3.0	39 34	3.0	39 34	ns ns	V <sub>CC</sub> = 5.0 V, C <sub>L</sub> = 50 pF, R <sub>L</sub> = 2.0 kΩ ± 5.0%. V <sub>CC</sub> = 5.0 V, C <sub>L</sub> = 15 pF, R <sub>L</sub> = 2.0 kΩ ± 5.0%.
t <sub>PLH3</sub> t <sub>PLH3</sub>	Propagation Delay Data-Output Enable to Q	3.0	32 27	3.0	42 37	3.0	42 37	ns ns	V <sub>CC</sub> = 5.0 V, C <sub>L</sub> = 50 pF, R <sub>L</sub> = 2.0 kΩ ± 5.0%. V <sub>CC</sub> = 5.0 V, C <sub>L</sub> = 15 pF, R <sub>L</sub> = 2.0 kΩ ± 5.0%.
t <sub>PHL4</sub> t <sub>PHL4</sub>	Propagation Delay Data-Output Enable to Q̄	3.0	20 15	3.0	26 21	3.0	26 21	ns ns	V <sub>CC</sub> = 5.0 V, C <sub>L</sub> = 50 pF, R <sub>L</sub> = 2.0 kΩ ± 5.0%. V <sub>CC</sub> = 5.0 V, C <sub>L</sub> = 15 pF, R <sub>L</sub> = 2.0 kΩ ± 5.0%.
t <sub>PLH4</sub> t <sub>PLH4</sub>	Propagation Delay Data-Output Enable to Q̄	3.0	35 30	3.0	46 41	3.0	46 41	ns ns	V <sub>CC</sub> = 5.0 V, C <sub>L</sub> = 50 pF, R <sub>L</sub> = 2.0 kΩ ± 5.0%. V <sub>CC</sub> = 5.0 V, C <sub>L</sub> = 15 pF, R <sub>L</sub> = 2.0 kΩ ± 5.0%.
V <sub>SUH</sub>	Logical "1" Setup Voltage	2.5		2.5		2.5		V	V <sub>CC</sub> = 5.0 V, C <sub>L</sub> = 50 pF, R <sub>L</sub> = 2.0 kΩ ± 5.0%.
V <sub>SUL</sub>	Logical "0" Setup Voltage		0.4		0.4		0.4	V	V <sub>CC</sub> = 5.0 V, C <sub>L</sub> = 50 pF, R <sub>L</sub> = 2.0 kΩ ± 5.0%.

**NOTES:**

1. The D input pulse generator has the following characteristics: V<sub>GEN</sub> = 3.0 V, t<sub>r</sub> ≤ 15 ns, t<sub>f</sub> ≤ 6.0 ns, t<sub>p</sub> = 30 ns and Z<sub>OUT</sub> = 50 Ω except when measuring V<sub>SETUP</sub>.
2. The enable pulse generator is identical to the D input pulse generator.
3. C<sub>L</sub> = 50 pF ± 10%, which includes probe and jig capacitance.
4. R<sub>L</sub> = 2.0 kΩ ± 5.0%.
5. All diodes are 1N3064 or equivalent.
6. V<sub>SETUP</sub> is to be measured 500 ns minimum after input transition to assure that the device has latched with minimum setup and maximum hold conditions applied to inputs.
7. Apply 0.0 V/3.0 V–5.0 V/0.0 V momentary pulse 500 ns minimum prior to measurement.
8. For all t<sub>PLH</sub> and V<sub>SUH</sub> tests, preset output into the ZERO state prior to making test.
9. For all t<sub>PHL</sub> and V<sub>SUL</sub> tests, preset output into ONE state prior to making test.
10. The limits specified for C<sub>L</sub> = 15 pF are guaranteed but not tested.